































Exams for group M17-304

Fri, 07 Dec	14:30 — 16:05	TEST	Management and Marketing  Stepanova E.B., Prohorov I.V.  A-100
Mon, 24 Dec	09:20 — 11:00	ATT	High-energy Single Diode Lasers  Bezotosnyy V.V.  FIAN
Mon, 24 Dec	11:05 — 12:40	ATT	Interaction of Laser Radiation and Matter  Zavestovskaya I.N.  FIAN
Mon, 24 Dec	12:45 — 14:20	ATT	Practical Training (Research Work)  Zavestovskaya I.N., Zaslavitskiy I.I., Bezotosnyy V.V., Cheshev E.A., Fronya A.A., Popov Y.M., Marmalyuk A.A., Krohin O.N., Kanavin A.P.  FIAN
Tue, 25 Dec	08:30 — 11:50	TEST	Theoretical Quantum Electronics  Zubarev I.G.  D-314
Tue, 25 Dec	12:45 — 14:20	TEST	Principles of Nuclear Technologies  Apse V.A.  B-100
Wed, 26 Dec	12:45 — 14:20	TEST	Computer Technology  Krasavin A.V.  V-106
Thu, 27 Dec	10:15 — 11:50	ATT	Semiconductor Disk Lasers  Kozlovskiy V.I.  FIAN
Thu, 27 Dec	12:45 — 14:20	ATT	Diode-Pumped Lasers  Cheshev E.A.  FIAN
Fri, 28 Dec	12:00 — 14:20	TEST	Legal and International Aspects of Nonproliferation and Nuclear Materials Safety.  Baratova A.A., Bogdanovich R.B., Kulikov E.G.  B-100
Thu, 10 Jan	09:00 — 13:00	EXAM	Interaction of Laser Radiation and Matter  Zavestovskaya I.N.  98-3
Mon, 14 Jan	09:00 — 13:00	EXAM	Diode-Pumped Lasers  Cheshev E.A.  FIAN
Fri, 18 Jan	09:00 — 13:00	EXAM	Semiconductor Disk Lasers  Kozlovskiy V.I.  FIAN
Tue, 22 Jan	09:00 — 13:00	EXAM	High-energy Single Diode Lasers  Bezotosnyy V.V.  FIAN
Sat, 26 Jan	09:00 — 13:00	EXAM	Practical Training (Research Work)  Popov Y.M., Marmalyuk A.A., Krohin O.N., Zaslavitskiy I.I., Cheshev E.A., Zavestovskaya I.N., Fronya A.A.  FIAN